

Substitute Form PTO-1449 (Modified)  <b>Information Disclosure Statement</b> by Applicant (Use several sheets if necessary)  (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office <b>MAR 29 2002</b>	Attorney's Docket No. 09712-055001	Application No. 10/025,595
	Applicant Peter de Groot		
	Filing Date December 18, 2001	Group Art Unit	

**U.S. Patent Documents**


Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
<i>all</i>	AA	4,340,306	07/20/82	Balasubramanian			
	AB	4,869,593	09/26/89	Biegen			
	AC	5,239,178	08/24/93	Dermdinger et al.			
	AD	5,398,113	03/14/95	de Groot			
	AE	5,737,084	04/07/98	Ishihara			

**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AF							

**Other Documents (include Author, Title, Date, and Place of Publication)**

Examiner Initial	Desig. ID	Document
<i>all</i>	AG	Caber, Paul J., "Interferometric Profiler for Rough Surfaces", <i>Applied Optics</i> , Vol. 32, No. 19, July 1, 1993, pp. 3438-3441
	AH	Dresel, Thomas et al., "Three-dimensional sensing of rough surfaces by coherence radar", <i>Applied Optics</i> , Vol. 31, No. 7, March 1, 1992, pp. 919-925
	AI	Tiziani H.J. et al., "Chromatic confocal microscopy with microlenses", <i>Journal of Modern Optics</i> , Vol. 43, No. 1, 1996, pp. 155-163
	AJ	Tiziani H.J. et al., "Three-dimensional analysis by a microlens-array confocal arrangement", <i>Applied Optics</i> , Vol. 33, No. 4, February 1, 1994, pp. 567-572

Examiner Signature 	Date Considered 2/22/05
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	